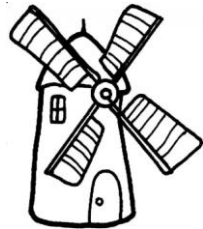
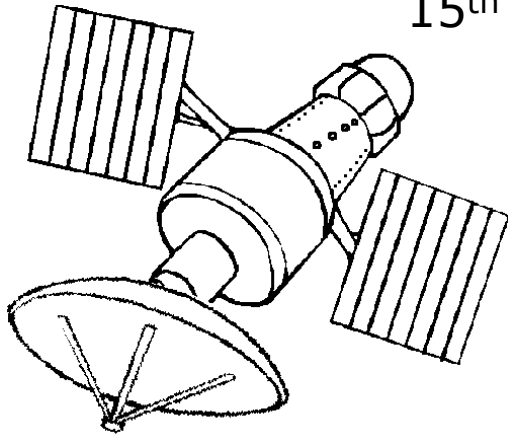


15th Geant4 Collaboration Workshop
ESTEC, 4-8 Oct 2010



Problems and requirements of space users

Giovanni Santin*



*Space Environments and Effects Analysis Section
European Space Agency
ESTEC*

** on loan from RHEA Tech Ltd*



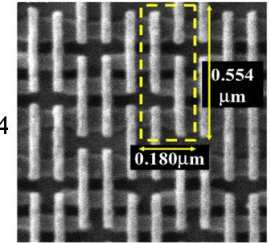
- A personal interpretation of status of electron simulations triggered by
 - Our internal analyses at ESA
 - Recent discussions with people involved in ESA contracts
 - Discussions at space users workshops
- Old ESA internal tests of low energy ion stopping powers
 - Still to be updated with recent releases (my apologies)
- Some other remarks

Electrons in Silicon

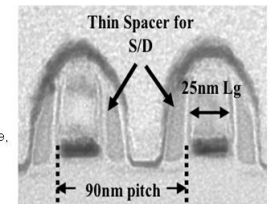
- Decreasing semiconductor feature sizes, comparable with ion track structure size
 - Detailed description of high density ionisation volume around particle tracks
 - Precise tracking of low energy electrons
 - New models for emission of lower energy delta rays
 - Charge densities?
 - Local temporary electric fields around ion track?
- Single delta rays will cause SEE's
 - Detailed tracking of electron ionisation and related fluctuations
- Anisotropic tracking in lattice?

Trends in Advanced Technology Nodes

- Decreasing feature sizes are leading to an overall reduction in critical charge
 - IBM 65 nm SOI critical charge around 0.14 fC – 0.24 fC (1500 electrons) [1]
- Recent publication from IBM details a 22 nm SOI technology node [2]
 - SRAM cell area of $0.1 \mu\text{m}^2$
 - Estimated critical charge of 0.08 fC, approximately 1.8 keV (500 electrons)



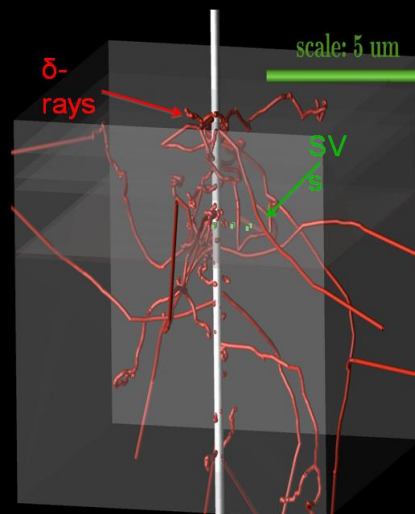
0.1 μm^2 SRAM after [2].



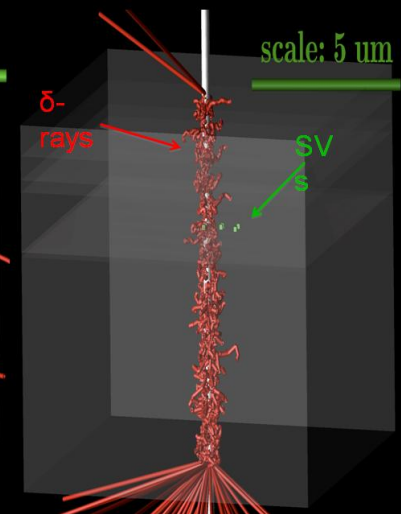
TEM of 22 nm devices after [2].
King, TNS 2010

[1] Rodbell, K.P., et al, "Low-Energy Proton-Induced Single-Event Upsets in 65 nm Node, Silicon-on-Insulator, Latches and Memory Cells," IEEE Trans. Nucl. Sci. Dec. 2007.
[2] Haran, B.S., et al, "22 nm technology compatible fully functional 0.1 μm^2 6T-SRAM cell," IEDM Dec. 2008.

28 GeV Fe Strike



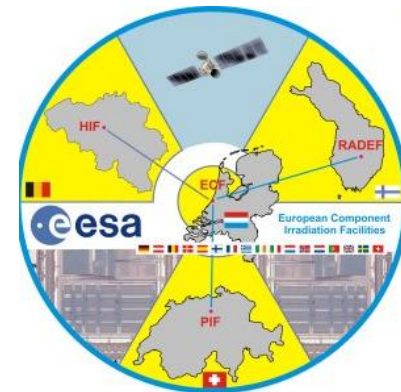
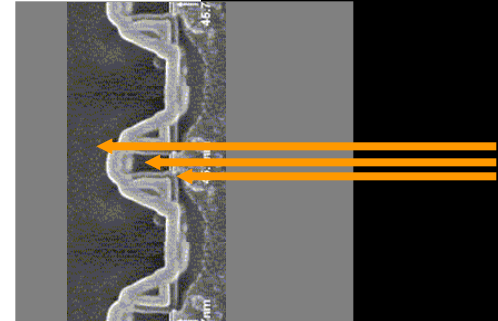
280 MeV Fe Strike



King, TNS 2010

Ion stopping power and fluctuations

- Ion stopping power and ranges for
 - Low energy (heavy) ion beams for ground testing
 - Recoils and fragments from proton and ion interactions
- Precise local energy deposition of ions
 - In sensitive volume (not at device entry surface)
 - With correct fluctuation (not only nominal, average stopping power)
 - With correct charge (validity of “effective charge” approach?)
- One example: Radiation Effects Facility (RADEF)
 - JYFL Accelerator Laboratory, Jyväskylä, Finland
 - One of the ESA’s European Component Irradiation Facilities (ECIF)
 - Heavy ion cocktail (7 ion species from N to Xe)
 - Energy of < 9.3 MeV/nuc
 - LET in Si from ~ 2 to 60 MeV/(mg/cm²)



Test of ion stopping power and straggling

Simulation setup

- GRAS v2.3 (Geant4 9.1, 09-01-ref-02)
- GRAS v2.4 (Geant4 9.2.p01 and 9.3.b01)
 - No big changes in GRAS w.r.t. v2.3
- Will be repeated with Geant4 9.3 and 9.4
- Geometry: MULASSIS type:
 - Vacuum
 - Silicon: 1 μ m (thin) or 10 μ m (thick)
 - Vacuum



Vacuum – Silicon – Vacuum

- Source
 - ^{131}Xe and ^{84}Kr , 0 \rightarrow 10 MeV/nuc
- Physics
 - em_standard (G4ionIonisation)
 - em_standardICRU73
 - Cuts: 1 μ m

```
# geometry
/gras/geometry/type mulassis
/geometry/layer/delete 0
/geometry/layer/shape slab
/geometry/layer/add 0 Vacuum 2 10.0 mm
/geometry/layer/add 1 Silicon 8 0.001 mm
/geometry/layer/add 2 Vacuum 2 10.0 mm
/geometry/update

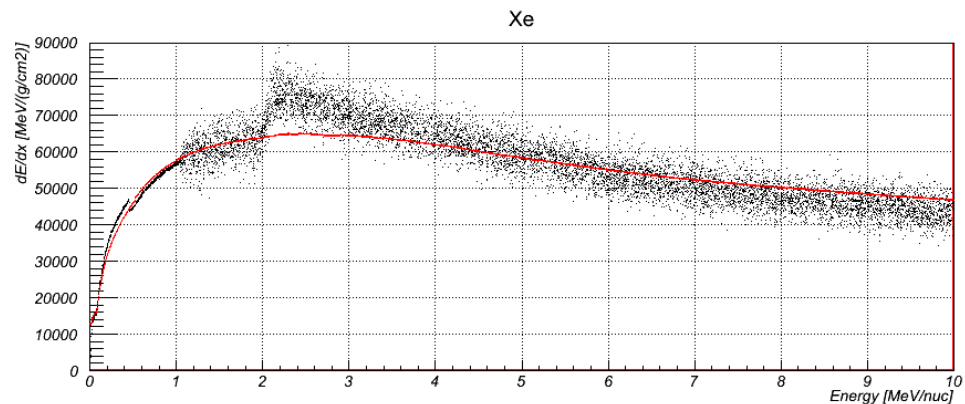
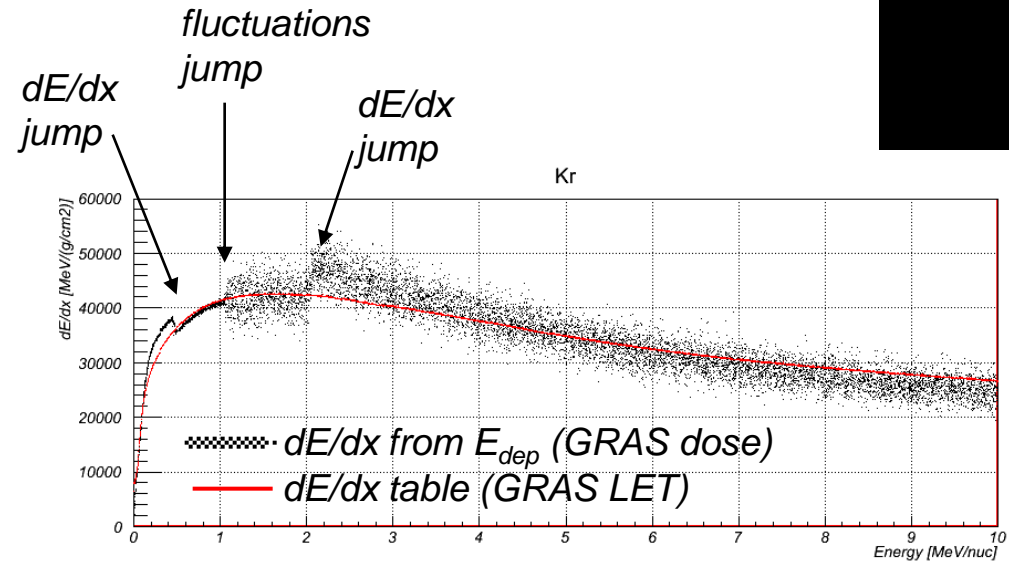
# source
/gps/particle ion
/gps/ion 54 131

# flat spectrum
/gps/ene/type Arb
/gps/hist/type arb
/gps/ene/min 0. MeV
/gps/ene/max 1310. MeV
/gps/hist/point 0. 1.
/gps/hist/point 1310. 1.
/gps/hist/inter Lin

# physics
/gras/physics/addPhysics em_standard
/gras/physics/setCuts 0.001 mm
```

Geant4 9.1 1 μm target

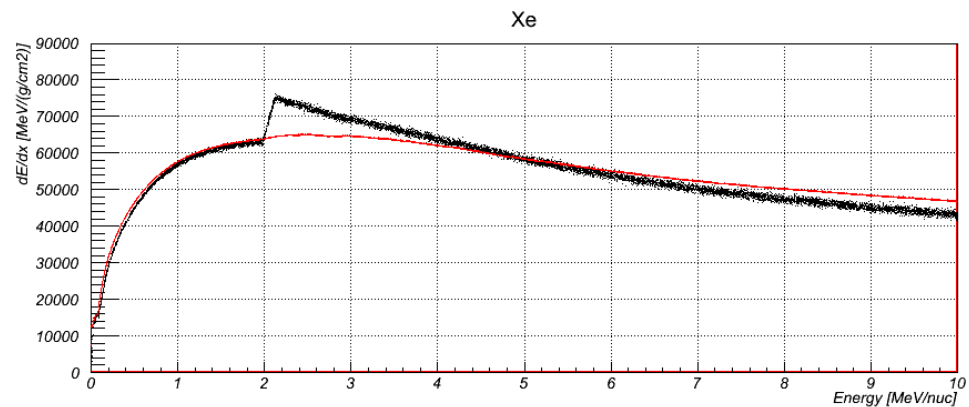
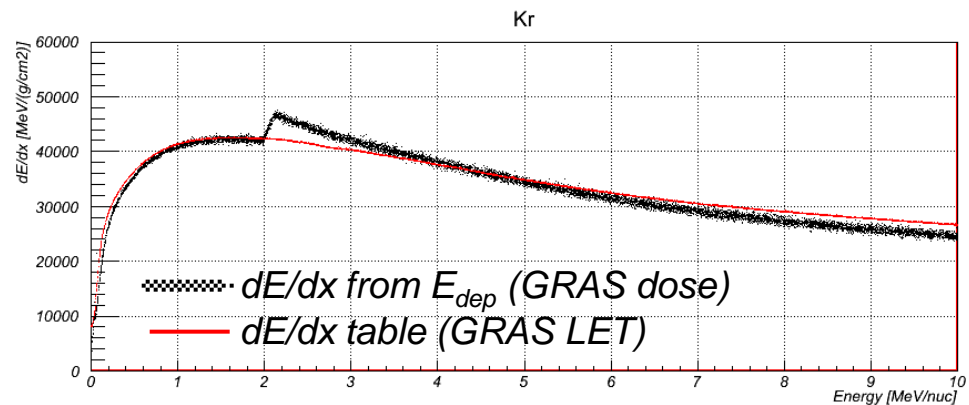
- Thickness: 1 μm
- Cuts: 1 μm
- These were the first results, with obvious problems, which prompted the discussion at the stdEM meeting, CERN, March 2008



Geant4 09-01-ref-02

1 μm target

- Thickness: 1 μm
- Cuts: 1 μm
- Prompt response from V.Ivantchenko, fixes included in reference tag 09-01-ref-02
- Changes w.r.t. Geant4 9.1
 - No jump in fluctuations (OK)
 - Smaller fluctuations (better?)
 - Discrepancy between models at transition (2 MeV) with linear interpolation in small range (2.0-2.5 MeV ?)



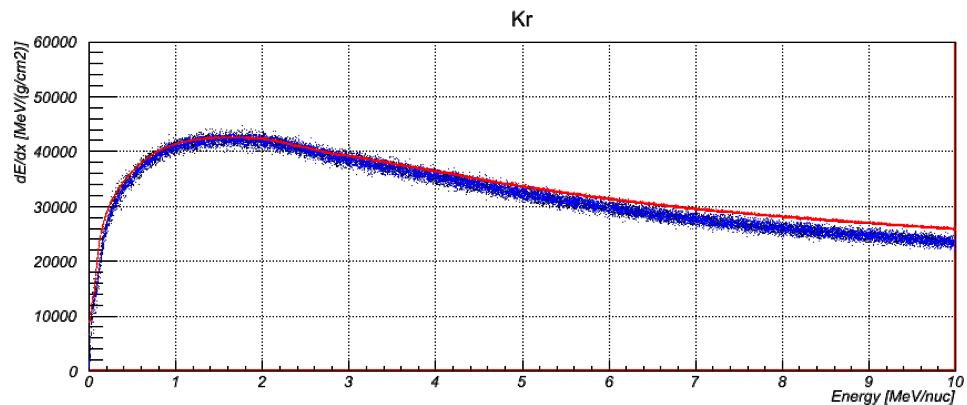
Geant4 9.2.p01 and 9.3.b01

1 μm target

em_standard

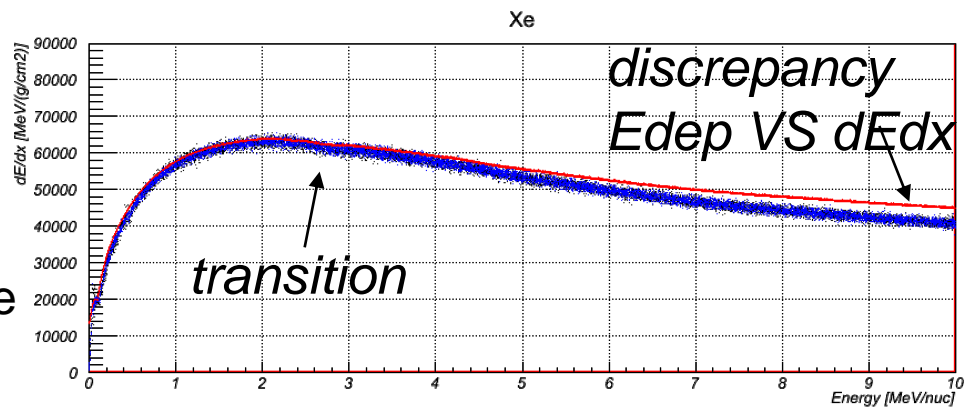
Notes w.r.t. 09-01-ref-02

- No big jump in dE/dx (OK)
- Some (really minor) features observable at model transition
- Still differences w.r.t. nominal dE/dx at higher energies
- Same fluctuations (OK?)



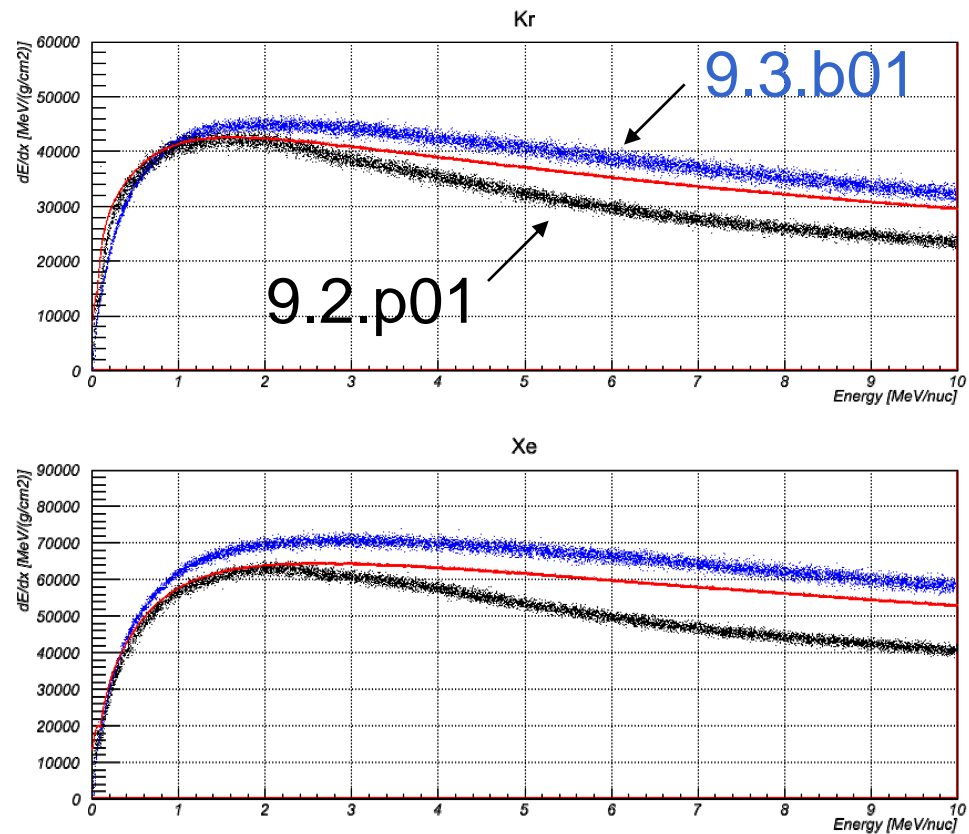
9.2.p01 and 9.3.b01 seem indistinguishable

“Nominal” dE/dx from em_calculator (red) is the same

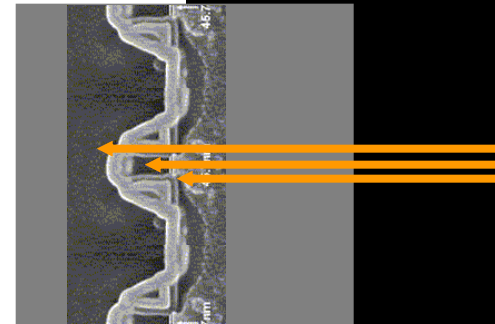
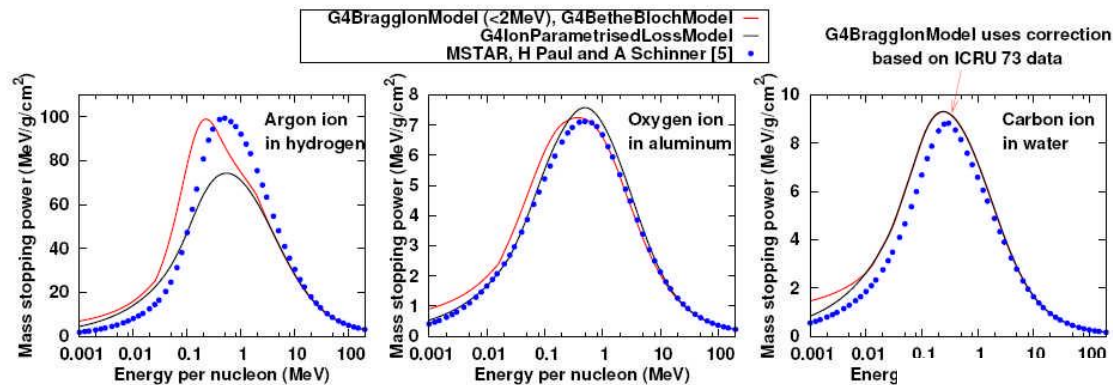


Geant4 9.2.p01 and 9.3.b01 1 μm target em_standardICRU73

- Significant change of absolute dose deposition in 9.3.b01 w.r.t. 9.2.p01
- “Nominal” dEdx from em_calculator (red) is the same for 9.3.b01 and 9.2.p01, but different w.r.t. em_standard
- The test will be repeated w/ Geant4 9.3 and 9.4

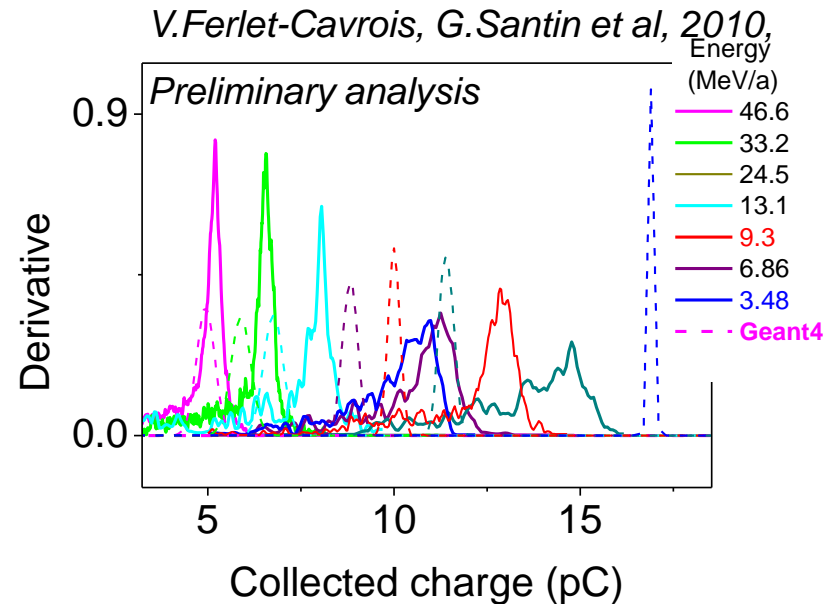


Ion stopping power recent developments



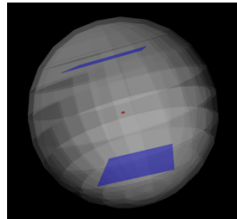
Open questions

- status of ion stopping power after ICRU73 implementation
- status of ion ionisation fluctuation models
- validity of ion and proton ionisation in short steps (thin layers) e.g. for deep sub micron technologies
- theoretical validity, validation and present limitations of ion effective charge approach



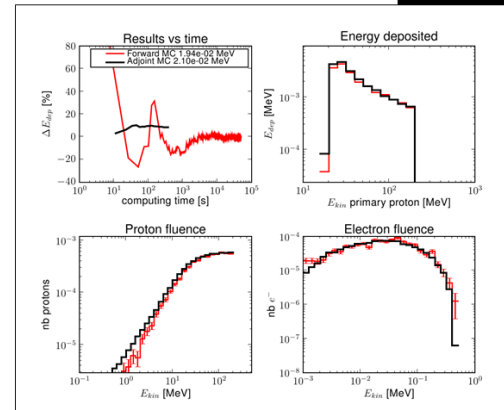
Reverse MC status and upgrades

Reverse MC: comparison VS forward Protons, simple geometry



- Difference in total computed dose $< \sim 5\%$
- Reverse MC method more rapid than forward by orders of magnitude

- Proton source
 - [0.1keV, 200MeV]
 - E^{-1} spectrum



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- Reverse MC developments could be made easier by improved Geant4 design / S/W architecture
- Hopefully addressed in new Geant4 architecture studies

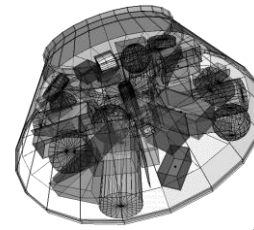
Engineering margins

Confidence in simulation results

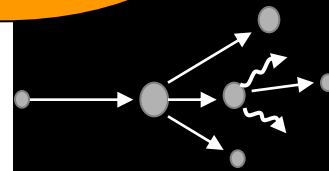
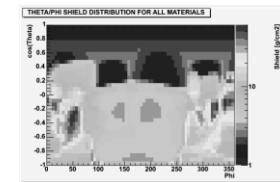
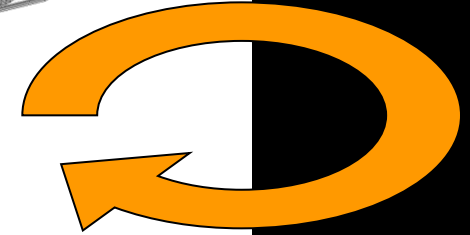
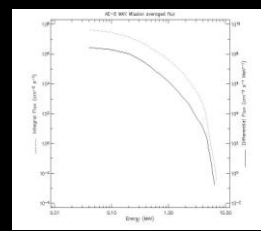
- Typical radiation analysis is iterative process with chain of calculations based on models, each with statistical and systematic uncertainties
 - Engineering margins should account for known and unknown unknowns to ensure mission survival in hostile environments
 - High margins imply extra costs (e.g. from weight of thick shielding, or system redundancy) and are sometimes showstoppers in feasibility studies – need justification, and should be reduced if possible

- 3-D Monte Carlo is assumed to be more precise than approximations based on 1-D calculations or ray tracing.
 - Is it really so? Contribution to the global error from particle transport models? Contribution from mistakes in MC tracking parameters, or misjudged confidence in physics model?
 - Can we quantify the global confidence in our Geant4 engineering calculations?

- Convergence criteria can help in confidence and computational speed



ConeXpress,
R.Lindberg,
ESA



esa galileo navigation
European Space Agency

ELSHIELD

Energetic Electron Shielding, Charging and Radiation Effects and Margins

- Analysis of problem areas in energetic electron penetration and interactions in S/C and P/L
- Tools: improve usability and physics modelling
- Validation of developments (also dedicated testing campaigns)
- Relationships with pre-flight testing and design margins
 Benchmarking and analyses to identify systematic deviations between simulation tools and engineering analysis processes performed as part of radiation hardness assurance and EMC assurance

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TAS-E led consortium
G4A1,
TRAD,
INTA,
DHC,
ONERA,
Arenum,
TAS France

Smart physics

- Geant4 can (now) deliver high quality output with best settings (?) , but results still show dependence on parameter tuning.
- Ideally: adaptive behaviour, with process and model change during tracking without user intervention
 - Standard behaviour determined by developer's knowledge (by e.g. energy, step length, distance from boundary,...)
 - Optionally responding to additional user requirements (e.g. by region, distance to sensitive volume,...)

Link to materials (point raised by Laurent Desorgher)

- Requirement for point tallies e.g. dose in a point for reverse MC
 - obtained from accessing LET tables in materials not necessarily present at that point nor anywhere in the geometry

NIEL analysis:

- Status of single scattering processes/models for protons and ions
- Status of NIEL calculation with different possible approaches